ONH836 Oxygen/Nitrogen/Hydrogen

Specification Sheet

This instrument now supports either Helium or Argon carrier gas. The type of carrier gas used may affect some instrument specifications, as indicated below.



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le)		Overage Overage
0.00005** to 50 mg		
0.00005** to 30 mg		
0.0002** to 30 mg		
0.0001** to 2.5 mg		
0.000025 mg or 0.3% RSD, whichever is greater		
0.000025 mg or 0.3% RSD, whichever is greater		
0.0001 mg or 0.3% RSD, whichever is greater		
0.00005 mg or 2% RSD, whichever is greater		
as, purge, and analysis delay)		
85 seconds	Oxygen, Ar Carrier Gas:	95 seconds
100 seconds	Nitrogen, Ar Carrier Gas:	130 seconds
90 seconds	Hydrogen, Ar Carrier Gas:	100 seconds
180 seconds	Cycle Time, Ar Carrier Gas	210 seconds
Standards (single or multi-point); m	anual; gas dose	
1 g (nominal)		
Non-Dispersive Infrared Absorption	; Thermal Conductivity	
 Anhydrous Magnesium Perchlorate (MgClO₄) Sodium Hydroxide on an Inert Base Copper Oxide, Copper Turnings Oxygen/Moisture Indicating Tube 		
Helium (99.99% pure), 22 psi (1.5 b	oar) ±5%	
Argon (99.999% pure), 22 psi (1.5 bar) ±5%		
Compressed Air, 40 psi (2.8 bar) $\pm 10\%$, source must be oil and water free		
Carbon Dioxide, 99.99% pure, 20 psi (1.4 bar) ±10%		
Nitrogen, 99.99% pure, 20 psi (1.4 bar) ±10%		
490 cc/minute		
280 cc/analysis		
Impulse furnace with current and power control 7500 Watts maximum, liquid cooled		
3.2 L LECO Coolant		
20 to 80%, non-condensing		
36 in. (91.5 cm) nominal; 39.25 in. (100 cm) with load head cover lift engaged		
27.75 in. (71 cm)		
30 in. (76 cm) without monitor; 31.5 in. (80 cm) with attached touch-screen monitor		
230 V~ (+10/-15%; at max load); 50A, 50/60 Hz, Single Phase; 12,500 BTU/hr [±]		
Analyzer: 410 lb. (186 kg) without to	ouch-screen monitor	
	0.00005** to 50 mg 0.00005** to 30 mg 0.0002** to 30 mg 0.0001** to 2.5 mg 0.000025 mg or 0.3% RSD, whicheve 0.000025 mg or 0.3% RSD, whichever 0.00005 mg or 2% RSD, whichever 0.00005 mg or 2% RSD, whichever 0.00005 mg or 2% RSD, whichever as, purge, and analysis delay) 85 seconds 100 seconds 90 seconds 180 seconds Standards (single or multi-point); m 1 g (nominal) Non-Dispersive Infrared Absorption • Anhydrous Magnesium Perchlorat • Sodium Hydroxide on an Inert Bas Helium (99.99% pure), 22 psi (1.5 k Argon (99.999% pure), 22 psi (1.5 k Argon (99.999% pure), 22 psi (1.5 k Compressed Air, 40 psi (2.8 bar) \pm 1 Carbon Dioxide, 99.99% pure, 20 psi (1.4 490 cc/minute 280 cc/analysis Impulse furnace with current and pc 3.2 L LECO Coolant 15 to 35°C (59 to 95°F) 20 to 80%, non-condensing 36 in. (91.5 cm) nominal; 39.25 in. 27.75 in. (71 cm) 30 in. (76 cm) without monitor; 31.3 230 V~ (+10/-15%; at max load); 5	0.00005** to 30 mg 0.00025** to 30 mg 0.00025** to 30 mg 0.00025 mg or 0.3% RSD, whichever is greater 0.00005 mg or 0.3% RSD, whichever is greater 0.00005 mg or 0.3% RSD, whichever is greater 0.00005 mg or 2% RSD, whichever is greater as, purge, and analysis delay) 85 seconds 0 seconds 100 s

*Use the following formula to calculate element concentration:

% element concentration = ((absolute element mass in mg)/(sample mass in mg))*100

**Lower range is calculated as 2 σ instrument blank deviation. Method range may differ

due to factors such as sample type and method parameters.

 $^{t}\text{Calculated}$ as 1 σ instrument blank deviation. Method precision may differ due to sample

inhomogeneity or other external factors.

[‡]Average output based on nominal operating parameters.

V~ denotes VAC.



Delivering the Right Results

⁺⁺Allow for a 6 in. (15 cm) minimum access area around all sides.

Part Numbers

ONH836-MC	O/N/H w/PC and touch-screen
ONH836-C	O/N/H w/PC
ONH836-HC	O/N/H w/PC and autocleaner
ONH836-HMC	O/N/H w/PC, touch-screen, and autocleaner

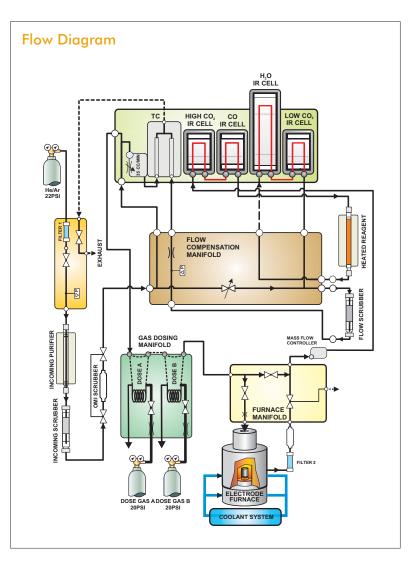
Theory of Operation

The ONH836 Oxygen/Nitrogen/Hydrogen system is designed for wide-range measurement of oxygen, nitrogen, and hydrogen content of steel, refractory metals, and other inorganic materials. The patented detection system supports the true simultaneous analysis of oxygen, nitrogen, and hydrogen during a single analysis, with one crucible and no carrier gas changeover. The instrument features custom MS Windows[®]-based software designed specifically for touch operation.

A pre-weighed sample is placed in a graphite crucible which is then heated in an impulse furnace to release analyte gases. An inert gas carrier, typically helium, sweeps the liberated analyte gases out of the furnace and through a Mass Flow Controller to a series of detectors. Oxygen present in the sample reacts with the graphite crucible to form CO and CO₂, which are detected using non-dispersive infrared (NDIR) cells. The gas then flows

through a heated reagent, where the CO is oxidized to form CO_2 , and H_2 is oxidized to form H_2O . The gas then continues through another set of NDIR cells where H_2O and CO_2 are detected. These analytes are then scrubbed out of the carrier gas stream. A patented Dynamic Flow Compensation (DFC) system is used to add carrier gas as a makeup for the gas lost during the scrubbing process. The final component in the flow stream is a Thermal Conductivity (TC) detector which is used to detect nitrogen.

The detection system is comprised of both NDIR and TC detectors. NDIR cells are based on the principle that CO, CO₂, and H₂O absorb infrared (IR) energy at unique wavelengths within the IR spectrum. Incident IR energy at these wavelengths is absorbed as the gases pass through the IR absorption cells. The complete set of CO and CO₂ NDIR cells is required to give the most accurate oxygen results for a wide range of sample types and concentrations. TC detection is based on the principle that heated filaments within a bridge circuit are maintained at a constant voltage in a flowing stream of carrier gas. Changes to the composition of the gas stream will cause a change to the resistance of the filaments. Nitrogen from the sample will cause this type of change, which is recorded as the analytical signal. The concentration of an unknown sample is determined relative to calibration standards. To reduce interferences from instrument drift, NDIR reference measurements of pure carrier gas are made prior to each analysis while TC reference measurements are made throughout each analysis.



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